

FORM PTO-1449
(REV. 7-80)U.S. DEPARTMENT OF COMMERCE
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501082.06 (98-0616.05)APPLICATION NO.
09/652,842INFORMATION DISCLOSURE STATEMENT
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Vishnu K. AgarwalFILING DATE
August 31, 2000GROUP ART UNIT
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U.S. PATENT DOCUMENTS

*EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BK	AA 3,649,886	03/14/72	Kooi	317	235	—
BK	AB 4,717,602	01/05/88	Yamazaki	427	53.1	—
BK	AC 5,232,871	08/03/93	Ho	437	190	—
BK	AD 5,552,339	09/03/96	Hsieh	437	190	—
BK	AE 5,733,816	03/31/98	Iyer et al.	438	592	—
BK	AF 6,136,690	10/24/00	Li	438	627	—
BK	AG 6,153,519	11/28/00	Jain et al.	438	681	—
BK	AH 6,204,203	03/20/01	Narwankar et al.	438	785	—
BK	AI 6,245,662	06/12/01	Naik et al.	438	622	—

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
BK	AJ 355011329 A	01/26/80	JP (Abstract only)	—	—	X	
BK	AK 410070091 A	03/10/98	JP (Abstract only)	—	—	X	

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

BK	AL	Anonymous, "Oxide-Free Dielectric/GaAs Interface With No Excess As", IBM Technical Disclosure Bulletin, Vol. 33, No. 11, April 1, 1991, p. 352.
BK	AM	Schulz, S.E. et al., "Influence of Water Preclean Before Selective Tungsten CVD on Surface Properties of Interconnect and Intermetal Dielectric Materials", Physica Status Solidi A, Vol. 145, No. 2, October 16, 1994, pp. 311-318.

EXAMINER

B.K. Kesavan

DATE CONSIDERED

04/04/02

* EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant(s).